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### Understanding Embedded - FPGAs (Field Programmable Gate Array)

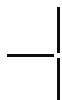
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Active
Number of LABs/CLBs	1452
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	81
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microchip-technology/a54sx16p-1vqg100m">https://www.e-xfl.com/product-detail/microchip-technology/a54sx16p-1vqg100m</a>



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# SX Family FPGAs

## General Description

The Actel SX family of FPGAs features a sea-of-modules architecture that delivers device performance and integration levels not currently achieved by any other FPGA architecture. SX devices greatly simplify design time, enable dramatic reductions in design costs and power consumption, and further decrease time to market for performance-intensive applications.

The Actel SX architecture features two types of logic modules, the combinatorial cell (C-cell) and the register cell (R-cell), each optimized for fast and efficient mapping of synthesized logic functions. The routing and interconnect resources are in the metal layers above the logic modules, providing optimal use of silicon. This enables the entire floor of the device to be spanned with an uninterrupted grid of fine-grained, synthesis-friendly logic modules (or “sea-of-modules”), which reduces the distance signals have to travel between logic modules. To minimize signal propagation delay, SX devices employ both local and general routing resources. The high-speed local routing resources (DirectConnect and FastConnect) enable very fast local signal propagation that is optimal for fast counters, state machines, and datapath logic. The general system of segmented routing tracks allows any logic module in the array to be connected to any other logic or I/O module. Within this system, propagation delay is minimized by limiting the number of antifuse interconnect elements to five (90 percent of connections typically use only three antifuses). The unique local and general routing structure featured in SX devices gives fast and predictable performance, allows 100 percent pin-locking with full logic utilization, enables concurrent PCB development, reduces design time, and allows designers to achieve performance goals with minimum effort.

Further complementing SX’s flexible routing structure is a hardwired, constantly loaded clock network that has been tuned to provide fast clock propagation with minimal clock skew. Additionally, the high performance of the internal logic has eliminated the need to embed latches or flip-flops in the I/O cells to achieve fast clock-to-out or fast input setup times. SX devices have easy to use I/O cells that do not require HDL instantiation, facilitating design reuse and reducing design and verification time.

## SX Family Architecture

The SX family architecture was designed to satisfy next-generation performance and integration requirements for production-volume designs in a broad range of applications.

### Programmable Interconnect Element

The SX family provides efficient use of silicon by locating the routing interconnect resources between the Metal 2 (M2) and Metal 3 (M3) layers (Figure 1-1 on page 1-2). This completely eliminates the channels of routing and interconnect resources between logic modules (as implemented on SRAM FPGAs and previous generations of antifuse FPGAs), and enables the entire floor of the device to be spanned with an uninterrupted grid of logic modules.

Interconnection between these logic modules is achieved using The Actel patented metal-to-metal programmable antifuse interconnect elements, which are embedded between the M2 and M3 layers. The antifuses are normally open circuit and, when programmed, form a permanent low-impedance connection.

The extremely small size of these interconnect elements gives the SX family abundant routing resources and provides excellent protection against design pirating. Reverse engineering is virtually impossible because it is extremely difficult to distinguish between programmed and unprogrammed antifuses, and there is no configuration bitstream to intercept.

Additionally, the interconnect elements (i.e., the antifuses and metal tracks) have lower capacitance and lower resistance than any other device of similar capacity, leading to the fastest signal propagation in the industry.

### Logic Module Design

The SX family architecture is described as a “sea-of-modules” architecture because the entire floor of the device is covered with a grid of logic modules with virtually no chip area lost to interconnect elements or routing. The Actel SX family provides two types of logic modules, the register cell (R-cell) and the combinatorial cell (C-cell).

## Boundary Scan Testing (BST)

All SX devices are IEEE 1149.1 compliant. SX devices offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. These functions are controlled through the special test pins in conjunction with the program fuse. The functionality of each pin is described in Table 1-2. In the dedicated test mode, TCK, TDI, and TDO are dedicated pins and cannot be used as regular I/Os. In flexible mode, TMS should be set HIGH through a pull-up resistor of 10 k $\Omega$ . TMS can be pulled LOW to initiate the test sequence.

The program fuse determines whether the device is in dedicated or flexible mode. The default (fuse not blown) is flexible mode.

Table 1-2 • Boundary Scan Pin Functionality

Program Fuse Blown (Dedicated Test Mode)	Program Fuse Not Blown (Flexible Mode)
TCK, TDI, TDO are dedicated BST pins.	TCK, TDI, TDO are flexible and may be used as I/Os.
No need for pull-up resistor for TMS	Use a pull-up resistor of 10 k $\Omega$ on TMS.

## Dedicated Test Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, users need to reserve the JTAG pins in Actel's Designer software by checking the "Reserve JTAG" box in "Device Selection Wizard" (Figure 1-7). JTAG pins comply with LVTTTL/TTL I/O specification regardless of whether they are used as a user I/O or a JTAG I/O. Refer to the Table 1-5 on page 1-8 for detailed specifications.

## Development Tool Support

The SX family of FPGAs is fully supported by both the Actel Libero® Integrated Design Environment (IDE) and Designer FPGA Development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, ModelSim® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the Libero IDE flow diagram (located on the Actel website) for more information.

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators, and the simulation results can be cross-probed with Silicon Explorer II, Actel integrated verification and logic analysis tool. Another tool included in the Designer software is the SmartGen core generator, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys®, and Cadence® Design Systems. The Designer software is available for both the Windows® and UNIX® operating systems.

## Probe Circuit Control Pins

The Silicon Explorer II tool uses the boundary scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-8 on page 1-7 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

## Design Considerations

The TDI, TCK, TDO, PRA, and PRB pins should not be used as input or bidirectional ports. Because these pins are active during probing, critical signals input through these pins are not available while probing. In addition, the Security Fuse should not be programmed because doing so disables the Probe Circuitry.

Figure 1-7 • Device Selection Wizard

## PCI Compliance for the SX Family

The SX family supports 3.3 V and 5.0 V PCI and is compliant with the PCI Local Bus Specification Rev. 2.1.

Table 1-6 • A54SX16P DC Specifications (5.0 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V <sub>CCA</sub>	Supply Voltage for Array		3.0	3.6	V
V <sub>CCR</sub>	Supply Voltage required for Internal Biasing		4.75	5.25	V
V <sub>CCI</sub>	Supply Voltage for I/Os		4.75	5.25	V
V <sub>IH</sub>	Input High Voltage <sup>1</sup>		2.0	V <sub>CC</sub> + 0.5	V
V <sub>IL</sub>	Input Low Voltage <sup>1</sup>		-0.5	0.8	V
I <sub>IH</sub>	Input High Leakage Current	V <sub>IN</sub> = 2.7		70	μA
I <sub>IL</sub>	Input Low Leakage Current	V <sub>IN</sub> = 0.5		-70	μA
V <sub>OH</sub>	Output High Voltage	I <sub>OUT</sub> = -2 mA	2.4		V
V <sub>OL</sub>	Output Low Voltage <sup>2</sup>	I <sub>OUT</sub> = 3 mA, 6 mA		0.55	V
C <sub>IN</sub>	Input Pin Capacitance <sup>3</sup>			10	pF
C <sub>CLK</sub>	CLK Pin Capacitance		5	12	pF
C <sub>IDSEL</sub>	IDSEL Pin Capacitance <sup>4</sup>			8	pF

### Notes:

1. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
2. Signals without pull-up resistors must have 3 mA low output current. Signals requiring pull-up must have 6 mA; the latter include, FRAME#, IRDY#, TRDY#, DEVSEL#, STOP#, SERR#, PERR#, LOCK#, and, when used, AD[63::32], C/BE[7::4]#, PAR64, REQ64#, and ACK64#.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).
4. Lower capacitance on this input-only pin allows for non-resistive coupling to AD[xx].

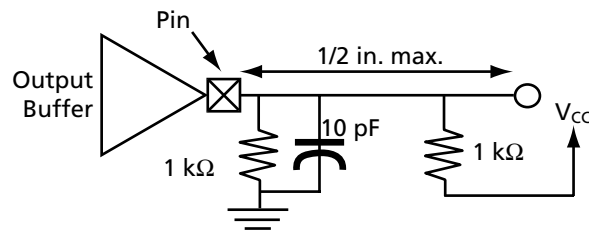
## A54SX16P AC Specifications for (PCI Operation)

Table 1-7 • A54SX16P AC Specifications for (PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 1.4^1$	-44		mA
		$1.4 \leq V_{OUT} < 2.4^1, ^2$	$-44 + (V_{OUT} - 1.4)/0.024$		mA
		$3.1 < V_{OUT} < V_{CC}^{1, ^3}$		EQ 1-1 on page 1-11	
	(Test Point)	$V_{OUT} = 3.1^3$		-142	mA
$I_{OL(AC)}$	Switching Current High	$V_{OUT} \geq 2.2^1$	95		mA
		$2.2 > V_{OUT} > 0.55^1$	$V_{OUT}/0.023$		
		$0.71 > V_{OUT} > 0^{1, ^3}$		EQ 1-2 on page 1-11	mA
	(Test Point)	$V_{OUT} = 0.71^3$		206	mA
$I_{CL}$	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$		mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load <sup>4</sup>	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load <sup>4</sup>	1	5	V/ns

### Notes:

1. Refer to the *V<sub>I</sub>* curves in Figure 1-9 on page 1-11. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half-size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.
2. Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.
3. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maxima (A and B) are provided with the respective diagrams in Figure 1-9 on page 1-11. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
4. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur, and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.



## Evaluating Power in SX Devices

A critical element of system reliability is the ability of electronic devices to safely dissipate the heat generated during operation. The thermal characteristics of a circuit depend on the device and package used, the operating temperature, the operating current, and the system's ability to dissipate heat.

You should complete a power evaluation early in the design process to help identify potential heat-related problems in the system and to prevent the system from exceeding the device's maximum allowed junction temperature.

The actual power dissipated by most applications is significantly lower than the power the package can dissipate. However, a thermal analysis should be performed for all projects. To perform a power evaluation, follow these steps:

1. Estimate the power consumption of the application.
2. Calculate the maximum power allowed for the device and package.
3. Compare the estimated power and maximum power values.

## Estimating Power Consumption

The total power dissipation for the SX family is the sum of the DC power dissipation and the AC power dissipation. Use EQ 1-5 to calculate the estimated power consumption of your application.

$$P_{\text{Total}} = P_{\text{DC}} + P_{\text{AC}}$$

EQ 1-5

## DC Power Dissipation

The power due to standby current is typically a small component of the overall power. The Standby power is shown in Table 1-12 for commercial, worst-case conditions (70°C).

Table 1-12 • Standby Power

I <sub>CC</sub>	V <sub>CC</sub>	Power
4 mA	3.6 V	14.4 mW

The DC power dissipation is defined in EQ 1-6.

$$P_{\text{DC}} = (I_{\text{standby}}) \times V_{\text{CCA}} + (I_{\text{standby}}) \times V_{\text{CCR}} + (I_{\text{standby}}) \times V_{\text{CCI}} + xV_{\text{OL}} \times I_{\text{OL}} + y(V_{\text{CCI}} - V_{\text{OH}}) \times V_{\text{OH}}$$

EQ 1-6

## AC Power Dissipation

The power dissipation of the SX Family is usually dominated by the dynamic power dissipation. Dynamic power dissipation is a function of frequency, equivalent capacitance, and power supply voltage. The AC power dissipation is defined in EQ 1-7 and EQ 1-8.

$$P_{\text{AC}} = P_{\text{Module}} + P_{\text{RCLKA Net}} + P_{\text{RCLKB Net}} + P_{\text{HCLK Net}} + P_{\text{Output Buffer}} + P_{\text{Input Buffer}}$$

EQ 1-7

$$P_{\text{AC}} = V_{\text{CCA}}^2 \times [(m \times C_{\text{EQM}} \times f_m)_{\text{Module}} + (n \times C_{\text{EQI}} \times f_n)_{\text{Input Buffer}} + (p \times (C_{\text{EQO}} + C_L) \times f_p)_{\text{Output Buffer}} + (0.5 \times (q_1 \times C_{\text{EQCR}} \times f_{q1}) + (r_1 \times f_{q1}))_{\text{RCLKA}} + (0.5 \times (q_2 \times C_{\text{EQCR}} \times f_{q2}) + (r_2 \times f_{q2}))_{\text{RCLKB}} + (0.5 \times (s_1 \times C_{\text{EQHV}} \times f_{s1}) + (C_{\text{EQHF}} \times f_{s1}))_{\text{HCLK}}]$$

EQ 1-8

## Definition of Terms Used in Formula

- m = Number of logic modules switching at  $f_m$
- n = Number of input buffers switching at  $f_n$
- p = Number of output buffers switching at  $f_p$
- q<sub>1</sub> = Number of clock loads on the first routed array clock
- q<sub>2</sub> = Number of clock loads on the second routed array clock
- x = Number of I/Os at logic low
- y = Number of I/Os at logic high
- r<sub>1</sub> = Fixed capacitance due to first routed array clock
- r<sub>2</sub> = Fixed capacitance due to second routed array clock
- s<sub>1</sub> = Number of clock loads on the dedicated array clock
- C<sub>EQM</sub> = Equivalent capacitance of logic modules in pF
- C<sub>EQI</sub> = Equivalent capacitance of input buffers in pF
- C<sub>EQO</sub> = Equivalent capacitance of output buffers in pF
- C<sub>EQCR</sub> = Equivalent capacitance of routed array clock in pF
- C<sub>EQHV</sub> = Variable capacitance of dedicated array clock
- C<sub>EQHF</sub> = Fixed capacitance of dedicated array clock
- C<sub>L</sub> = Output lead capacitance in pF
- f<sub>m</sub> = Average logic module switching rate in MHz
- f<sub>n</sub> = Average input buffer switching rate in MHz
- f<sub>p</sub> = Average output buffer switching rate in MHz
- f<sub>q1</sub> = Average first routed array clock rate in MHz
- f<sub>q2</sub> = Average second routed array clock rate in MHz
- f<sub>s1</sub> = Average dedicated array clock rate in MHz



**Step 1: Define Terms Used in Formula**

<b>Module</b>	$V_{CCA}$	3.3
Number of logic modules switching at $f_m$ (Used 50%)	$m$	264
Average logic modules switching rate $f_m$ (MHz) (Guidelines: $f/10$ )	$f_m$	20
Module capacitance $C_{EQM}$ (pF)	$C_{EQM}$	4.0
<b>Input Buffer</b>		
Number of input buffers switching at $f_n$	$n$	1
Average input switching rate $f_n$ (MHz) (Guidelines: $f/5$ )	$f_n$	40
Input buffer capacitance $C_{EQI}$ (pF)	$C_{EQI}$	3.4
<b>Output Buffer</b>		
Number of output buffers switching at $f_p$	$p$	1
Average output buffers switching rate $f_p$ (MHz) (Guidelines: $f/10$ )	$f_p$	20
Output buffers buffer capacitance $C_{EQO}$ (pF)	$C_{EQO}$	4.7
Output Load capacitance $C_L$ (pF)	$C_L$	35
<b>RCLKA</b>		
Number of Clock loads $q_1$	$q_1$	528
Capacitance of routed array clock (pF)	$C_{EQCR}$	1.6
Average clock rate (MHz)	$f_{q1}$	200
Fixed capacitance (pF)	$r_1$	138
<b>RCLKB</b>		
Number of Clock loads $q_2$	$q_2$	0
Capacitance of routed array clock (pF)	$C_{EQCR}$	1.6
Average clock rate (MHz)	$f_{q2}$	0
Fixed capacitance (pF)	$r_2$	138
<b>HCLK</b>		
Number of Clock loads	$s_1$	0
Variable capacitance of dedicated array clock (pF)	$C_{EQHV}$	0.61 5
Fixed capacitance of dedicated array clock (pF)	$C_{EQHF}$	96
Average clock rate (MHz)	$f_{s1}$	0

**Step 2: Calculate Dynamic Power Consumption**

$V_{CCA} \times V_{CCA}$	10.89
$m \times f_m \times C_{EQM}$	0.02112
$n \times f_n \times C_{EQI}$	0.000136
$p \times f_p \times (C_{EQO} + C_L)$	0.000794
$0.5 (q_1 \times C_{EQCR} \times f_{q1}) + (r_1 \times f_{q1})$	0.11208
$0.5 (q_2 \times C_{EQCR} \times f_{q2}) + (r_2 \times f_{q2})$	0
$0.5 (s_1 \times C_{EQHV} \times f_{s1}) + (C_{EQHF} \times f_{s1})$	0
$P_{AC} = 1.461 \text{ W}$	

**Step 3: Calculate DC Power Dissipation****DC Power Dissipation**

$$P_{DC} = (I_{\text{standby}}) \times V_{CCA} + (I_{\text{standby}}) \times V_{CCR} + (I_{\text{standby}}) \times V_{CCI} + X \times V_{OL} \times I_{OL} + Y(V_{CCI} - V_{OH}) \times V_{OH}$$

EQ 1-12

For a rough estimate of DC Power Dissipation, only use  $P_{DC} = (I_{\text{standby}}) \times V_{CCA}$ . The rest of the formula provides a very small number that can be considered negligible.

$$P_{DC} = (I_{\text{standby}}) \times V_{CCA}$$

$$P_{DC} = .55 \text{ mA} \times 3.3 \text{ V}$$

$$P_{DC} = 0.001815 \text{ W}$$

**Step 4: Calculate Total Power Consumption**

$$P_{\text{Total}} = P_{AC} + P_{DC}$$

$$P_{\text{Total}} = 1.461 + 0.001815$$

$$P_{\text{Total}} = 1.4628 \text{ W}$$

**Step 5: Compare Estimated Power Consumption against Characterized Power Consumption**

The estimated total power consumption for this design is 1.46 W. The characterized power consumption for this design at 200 MHz is 1.0164 W.

**Table 1-15 • Package Thermal Characteristics**

Package Type	Pin Count	$\theta_{jc}$	$\theta_{ja}$ Still Air	$\theta_{ja}$ 300 ft/min.	Units
Plastic Leaded Chip Carrier (PLCC)	84	12	32	22	°C/W
Thin Quad Flat Pack (TQFP)	144	11	32	24	°C/W
Thin Quad Flat Pack (TQFP)	176	11	28	21	°C/W
Very Thin Quad Flatpack (VQFP)	100	10	38	32	°C/W
Plastic Quad Flat Pack (PQFP) without Heat Spreader	208	8	30	23	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader	208	3.8	20	17	°C/W
Plastic Ball Grid Array (PBGA)	272	3	20	14.5	°C/W
Plastic Ball Grid Array (PBGA)	313	3	23	17	°C/W
Plastic Ball Grid Array (PBGA)	329	3	18	13.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	38.8	26.7	°C/W

**Note:** SX08 does not have a heat spreader.

**Table 1-16 • Temperature and Voltage Derating Factors\***

$V_{CCA}$	Junction Temperature						
	-55	-40	0	25	70	85	125
<b>3.0</b>	0.75	0.78	0.87	0.89	1.00	1.04	1.16
<b>3.3</b>	0.70	0.73	0.82	0.83	0.93	0.97	1.08
<b>3.6</b>	0.66	0.69	0.77	0.78	0.87	0.92	1.02

**Note:** \*Normalized to worst-case commercial,  $T_J = 70^\circ\text{C}$ ,  $V_{CCA} = 3.0\text{ V}$

## Register Cell Timing Characteristics

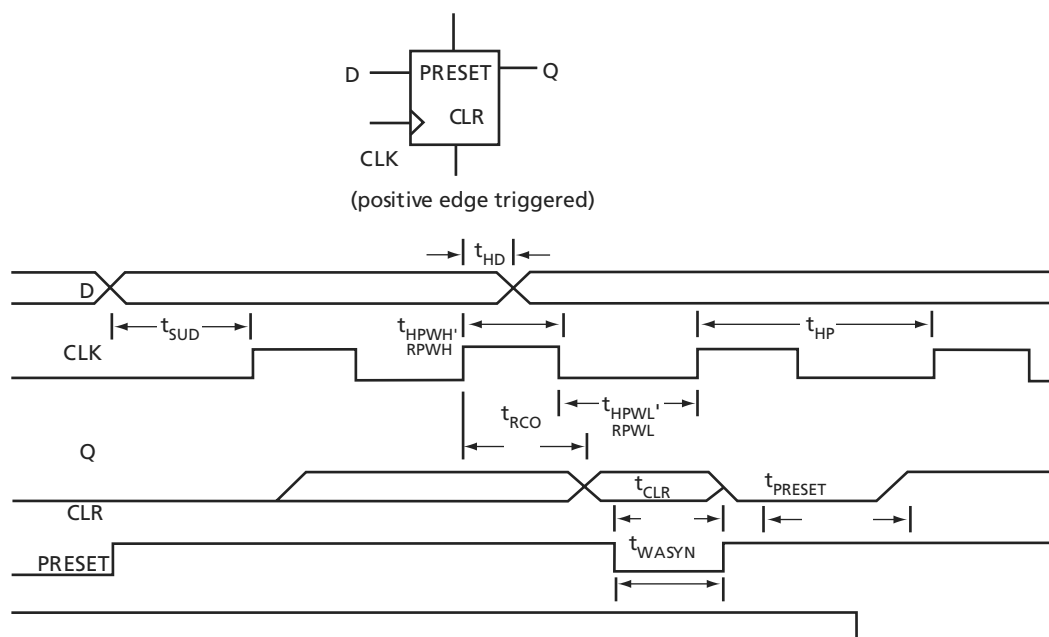


Figure 1-17 • Flip-Flops

## Timing Characteristics

Timing characteristics for SX devices fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all SX family members. Internal routing delays are device-dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design is complete. Delay values may then be determined by using the DirectTime Analyzer utility or performing simulation with post-layout delays.

## Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most time-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6% of the nets in a design may be designated as critical, while 90% of the nets in a design are typical.

## Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes five antifuse connections. This increases capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically up to 6 percent of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 8.4 ns delay. This additional delay is represented statistically in higher fanout ( $FO = 24$ ) routing delays in the datasheet specifications section.

## Timing Derating

SX devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

## 208-Pin PQFP

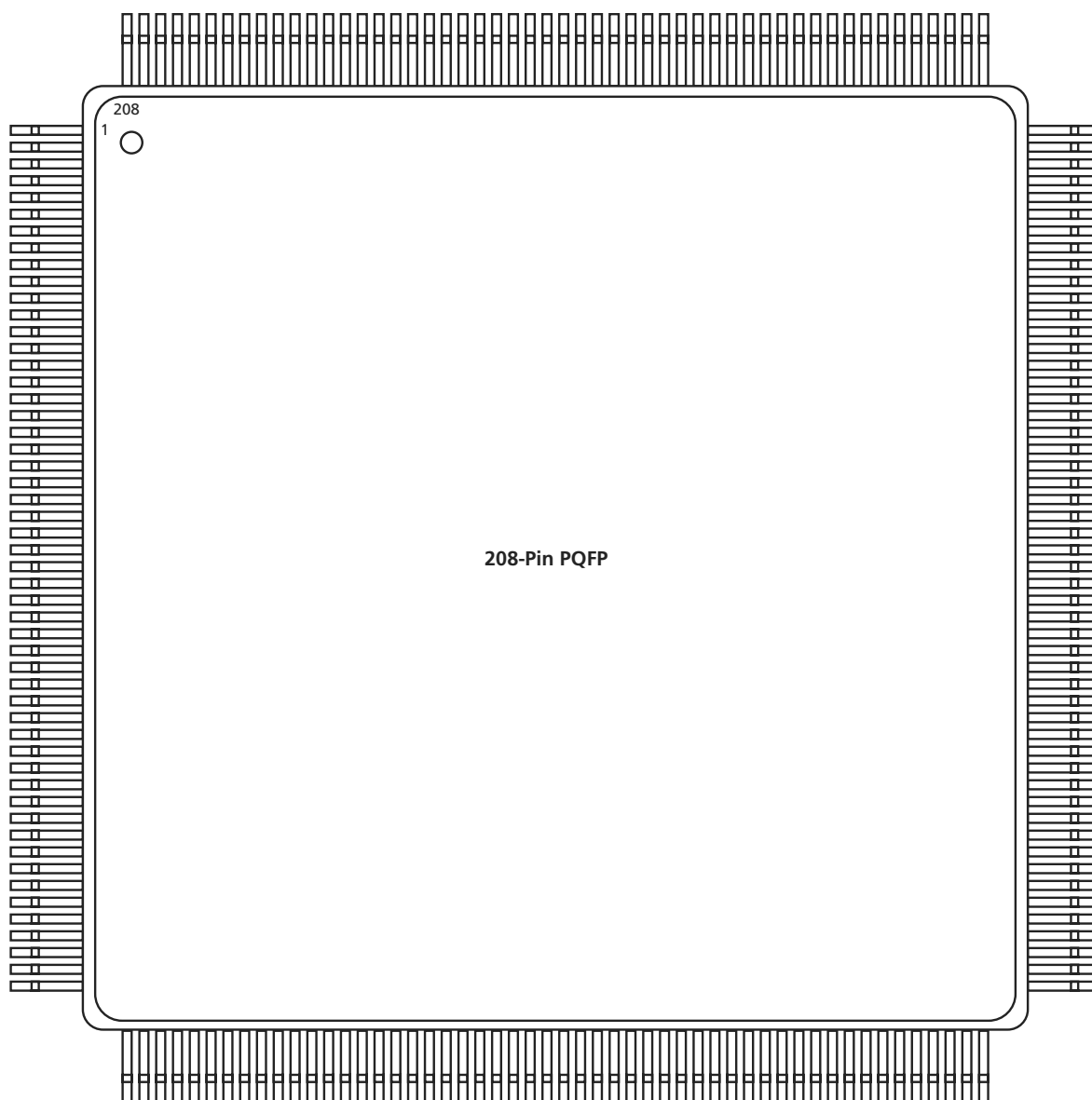


Figure 2-2 • 208-Pin PQFP (Top View)

### Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

208-Pin PQFP			
Pin Number	A545X08 Function	A545X16, A545X16P Function	A545X32 Function
73	NC	I/O	I/O
74	I/O	I/O	I/O
75	NC	I/O	I/O
76	PRB, I/O	PRB, I/O	PRB, I/O
77	GND	GND	GND
78	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
79	GND	GND	GND
80	V <sub>CCR</sub>	V <sub>CCR</sub>	V <sub>CCR</sub>
81	I/O	I/O	I/O
82	HCLK	HCLK	HCLK
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	NC	I/O	I/O
86	I/O	I/O	I/O
87	I/O	I/O	I/O
88	NC	I/O	I/O
89	I/O	I/O	I/O
90	I/O	I/O	I/O
91	NC	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	NC	I/O	I/O
95	I/O	I/O	I/O
96	I/O	I/O	I/O
97	NC	I/O	I/O
98	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
99	I/O	I/O	I/O
100	I/O	I/O	I/O
101	I/O	I/O	I/O
102	I/O	I/O	I/O
103	TDO, I/O	TDO, I/O	TDO, I/O
104	I/O	I/O	I/O
105	GND	GND	GND
106	NC	I/O	I/O
107	I/O	I/O	I/O
108	NC	I/O	I/O

208-Pin PQFP			
Pin Number	A545X08 Function	A545X16, A545X16P Function	A545X32 Function
109	I/O	I/O	I/O
110	I/O	I/O	I/O
111	I/O	I/O	I/O
112	I/O	I/O	I/O
113	I/O	I/O	I/O
114	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
115	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
116	NC	I/O	I/O
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	NC	I/O	I/O
120	I/O	I/O	I/O
121	I/O	I/O	I/O
122	NC	I/O	I/O
123	I/O	I/O	I/O
124	I/O	I/O	I/O
125	NC	I/O	I/O
126	I/O	I/O	I/O
127	I/O	I/O	I/O
128	I/O	I/O	I/O
129	GND	GND	GND
130	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
131	GND	GND	GND
132	V <sub>CCR</sub>	V <sub>CCR</sub>	V <sub>CCR</sub>
133	I/O	I/O	I/O
134	I/O	I/O	I/O
135	NC	I/O	I/O
136	I/O	I/O	I/O
137	I/O	I/O	I/O
138	NC	I/O	I/O
139	I/O	I/O	I/O
140	I/O	I/O	I/O
141	NC	I/O	I/O
142	I/O	I/O	I/O
143	NC	I/O	I/O
144	I/O	I/O	I/O

**Note:** \* Note that Pin 65 in the A545X32—PQ208 is a no connect (NC).

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
145	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
146	GND	GND	GND
147	I/O	I/O	I/O
148	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
149	I/O	I/O	I/O
150	I/O	I/O	I/O
151	I/O	I/O	I/O
152	I/O	I/O	I/O
153	I/O	I/O	I/O
154	I/O	I/O	I/O
155	NC	I/O	I/O
156	NC	I/O	I/O
157	GND	GND	GND
158	I/O	I/O	I/O
159	I/O	I/O	I/O
160	I/O	I/O	I/O
161	I/O	I/O	I/O
162	I/O	I/O	I/O
163	I/O	I/O	I/O
164	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
165	I/O	I/O	I/O
166	I/O	I/O	I/O
167	NC	I/O	I/O
168	I/O	I/O	I/O
169	I/O	I/O	I/O
170	NC	I/O	I/O
171	I/O	I/O	I/O
172	I/O	I/O	I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	NC	I/O	I/O
177	I/O	I/O	I/O
178	I/O	I/O	I/O
179	I/O	I/O	I/O
180	CLKA	CLKA	CLKA

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
181	CLKB	CLKB	CLKB
182	V <sub>CCR</sub>	V <sub>CCR</sub>	V <sub>CCR</sub>
183	GND	GND	GND
184	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
185	GND	GND	GND
186	PRA, I/O	PRA, I/O	PRA, I/O
187	I/O	I/O	I/O
188	I/O	I/O	I/O
189	NC	I/O	I/O
190	I/O	I/O	I/O
191	I/O	I/O	I/O
192	NC	I/O	I/O
193	I/O	I/O	I/O
194	I/O	I/O	I/O
195	NC	I/O	I/O
196	I/O	I/O	I/O
197	I/O	I/O	I/O
198	NC	I/O	I/O
199	I/O	I/O	I/O
200	I/O	I/O	I/O
201	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
202	NC	I/O	I/O
203	NC	I/O	I/O
204	I/O	I/O	I/O
205	NC	I/O	I/O
206	I/O	I/O	I/O
207	I/O	I/O	I/O
208	TCK, I/O	TCK, I/O	TCK, I/O

**Note:** \* Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).

## 144-Pin TQFP

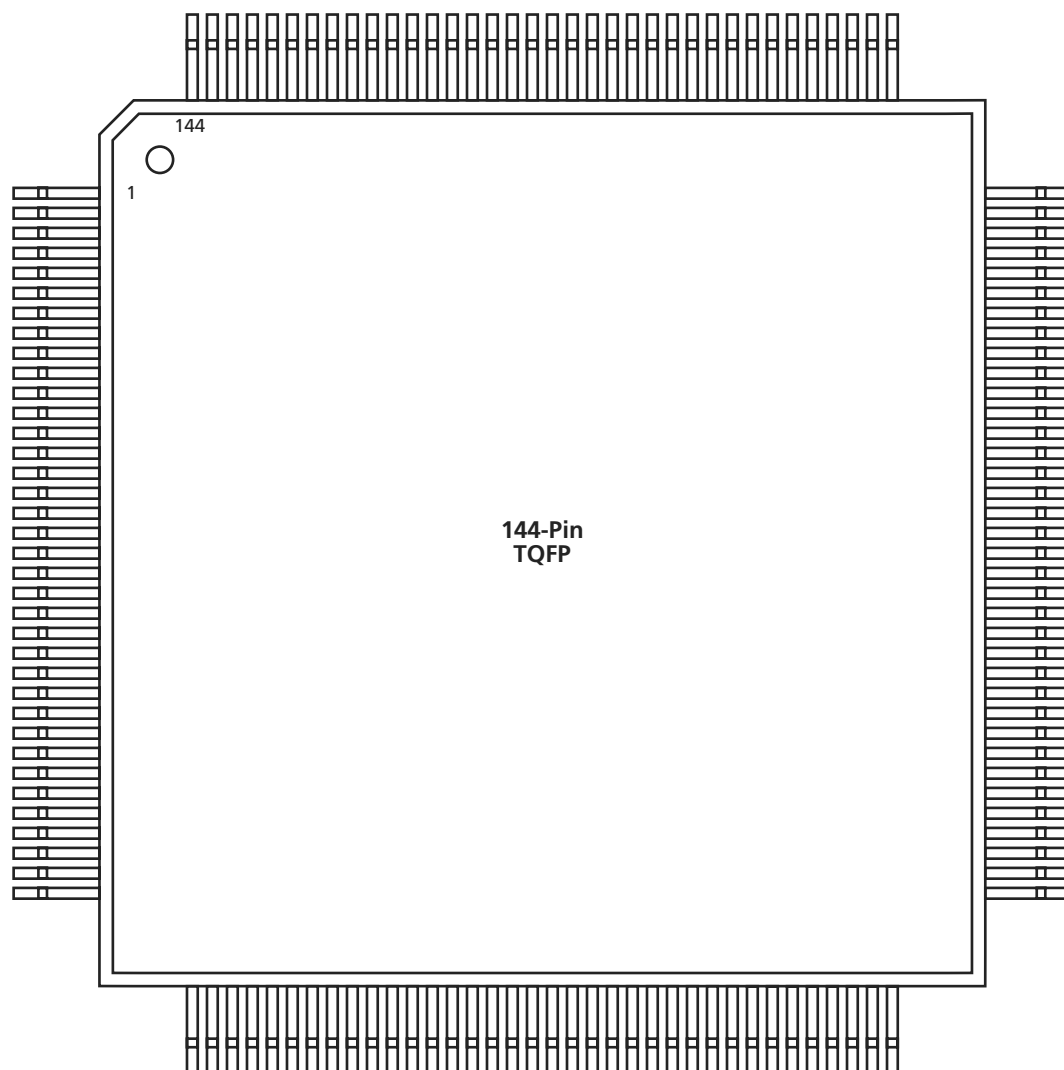


Figure 2-3 • 144-Pin TQFP (Top View)

### Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

## 176-Pin TQFP

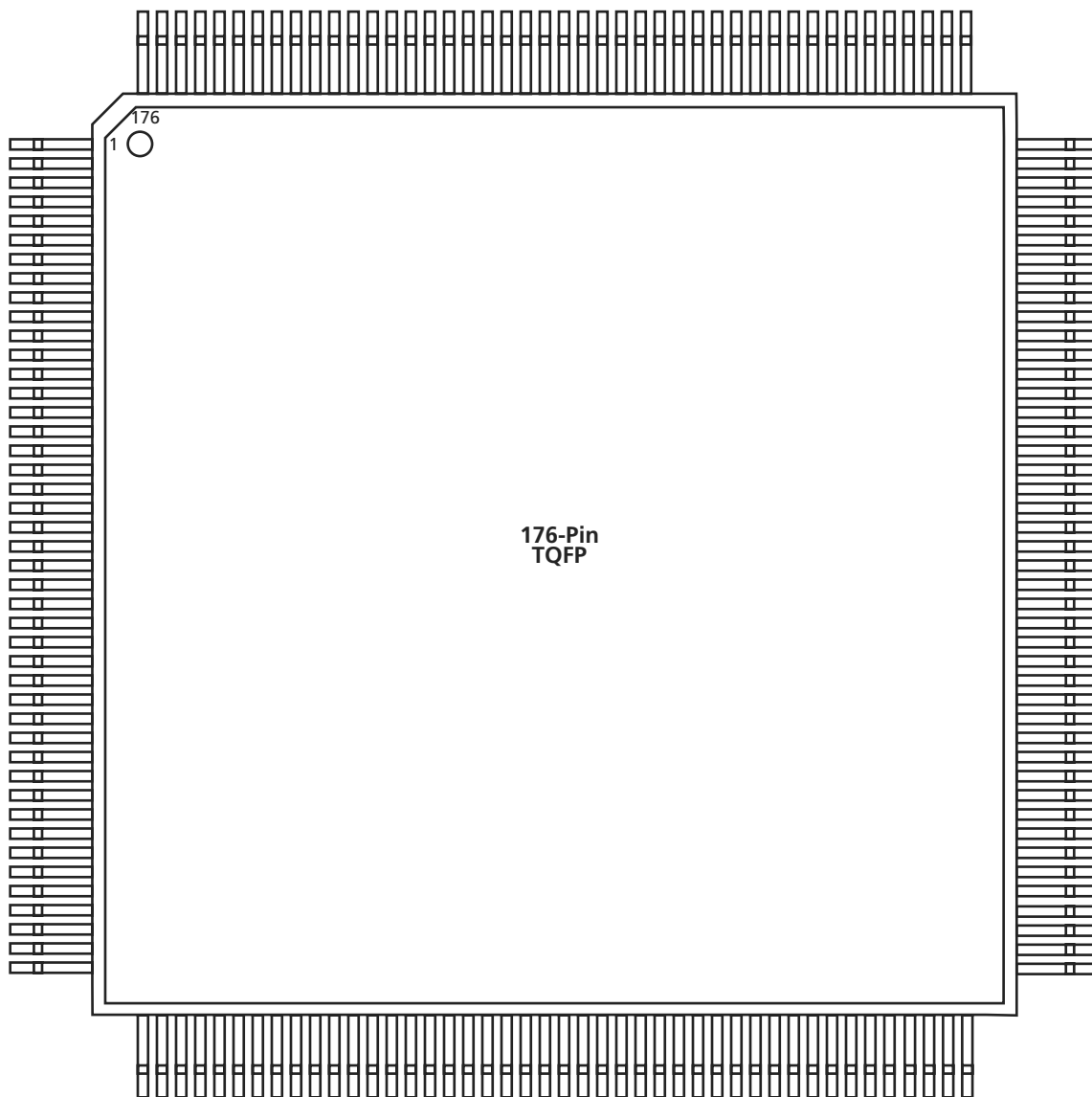


Figure 2-4 • 176-Pin TQFP (Top View)

### Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.



100-Pin VQFP		
Pin Number	A545X08 Function	A545X16, A545X16P Function
1	GND	GND
2	TDI, I/O	TDI, I/O
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	TMS	TMS
8	V <sub>CCI</sub>	V <sub>CCI</sub>
9	GND	GND
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	V <sub>CCI</sub>	V <sub>CCI</sub>
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	I/O	I/O
33	I/O	I/O
34	PRB, I/O	PRB, I/O

100-Pin VQFP		
Pin Number	A545X08 Function	A545X16, A545X16P Function
35	V <sub>CCA</sub>	V <sub>CCA</sub>
36	GND	GND
37	V <sub>CCR</sub>	V <sub>CCR</sub>
38	I/O	I/O
39	HCLK	HCLK
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	V <sub>CCI</sub>	V <sub>CCI</sub>
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	TDO, I/O	TDO, I/O
50	I/O	I/O
51	GND	GND
52	I/O	I/O
53	I/O	I/O
54	I/O	I/O
55	I/O	I/O
56	I/O	I/O
57	V <sub>CCA</sub>	V <sub>CCA</sub>
58	V <sub>CCI</sub>	V <sub>CCI</sub>
59	I/O	I/O
60	I/O	I/O
61	I/O	I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	I/O	I/O
67	V <sub>CCA</sub>	V <sub>CCA</sub>
68	GND	GND

100-Pin VQFP		
Pin Number	A545X08 Function	A545X16, A545X16P Function
69	GND	GND
70	I/O	I/O
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	I/O	I/O
75	I/O	I/O
76	I/O	I/O
77	I/O	I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O
81	I/O	I/O
82	V <sub>CCI</sub>	V <sub>CCI</sub>
83	I/O	I/O
84	I/O	I/O
85	I/O	I/O
86	I/O	I/O
87	CLKA	CLKA
88	CLKB	CLKB
89	V <sub>CCR</sub>	V <sub>CCR</sub>
90	V <sub>CCA</sub>	V <sub>CCA</sub>
91	GND	GND
92	PRA, I/O	PRA, I/O
93	I/O	I/O
94	I/O	I/O
95	I/O	I/O
96	I/O	I/O
97	I/O	I/O
98	I/O	I/O
99	I/O	I/O
100	TCK, I/O	TCK, I/O

## 313-Pin PBGA

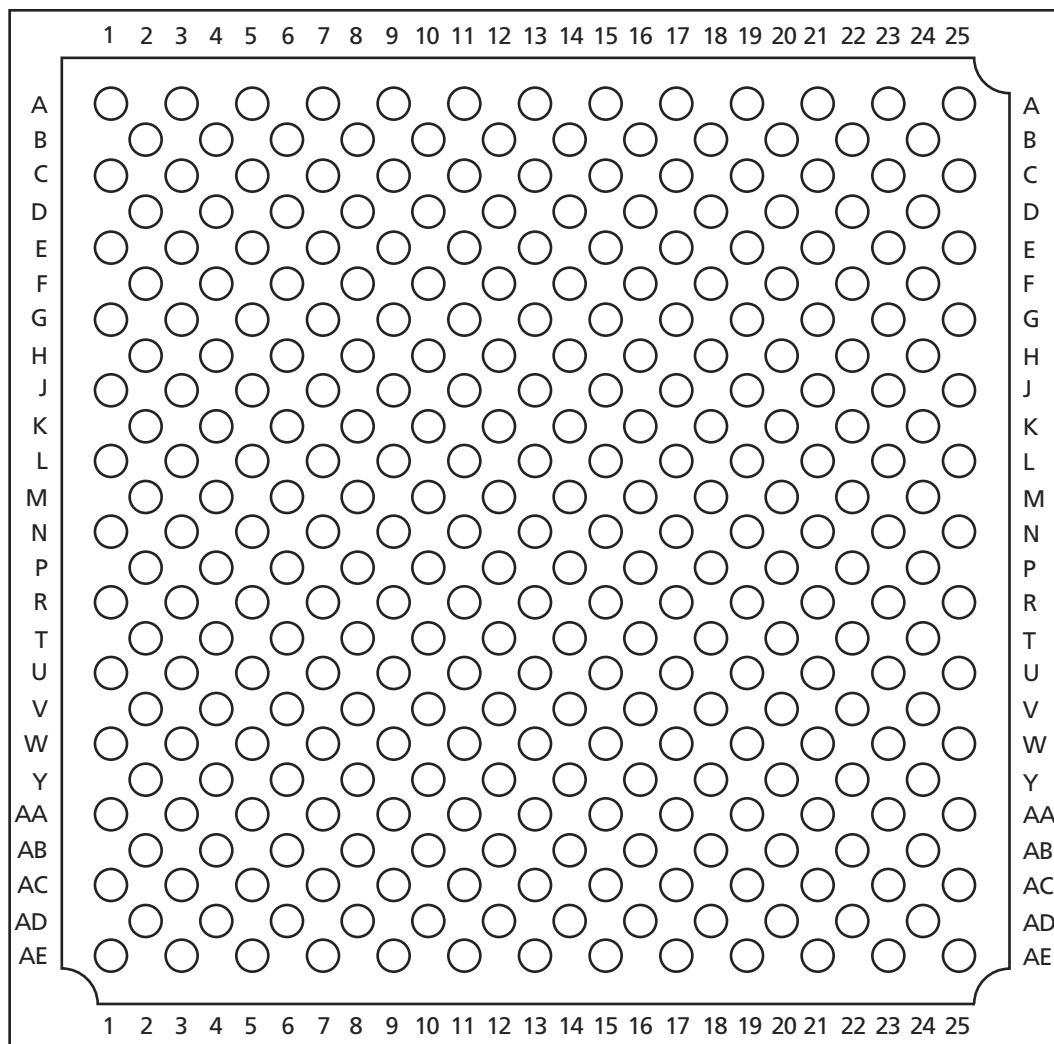


Figure 2-6 • 313-Pin PBGA (Top View)

### Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

313-Pin PBGA		313-Pin PBGA		313-Pin PBGA		313-Pin PBGA	
Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function
H20	I/O	L25	I/O	R5	I/O	V10	I/O
H22	V <sub>CCI</sub>	M2	I/O	R7	I/O	V12	I/O
H24	I/O	M4	I/O	R9	I/O	V14	I/O
J1	I/O	M6	I/O	R11	I/O	V16	NC
J3	I/O	M8	I/O	R13	GND	V18	I/O
J5	I/O	M10	I/O	R15	I/O	V20	I/O
J7	NC	M12	GND	R17	I/O	V22	V <sub>CCA</sub>
J9	I/O	M14	GND	R19	I/O	V24	V <sub>CCI</sub>
J11	I/O	M16	V <sub>CCI</sub>	R21	I/O	W1	I/O
J13	CLKA	M18	I/O	R23	I/O	W3	I/O
J15	I/O	M20	I/O	R25	I/O	W5	I/O
J17	I/O	M22	I/O	T2	I/O	W7	NC
J19	I/O	M24	I/O	T4	I/O	W9	I/O
J21	GND	N1	I/O	T6	I/O	W11	I/O
J23	I/O	N3	V <sub>CCA</sub>	T8	I/O	W13	V <sub>CCI</sub>
J25	I/O	N5	V <sub>CCR</sub>	T10	I/O	W15	I/O
K2	I/O	N7	I/O	T12	I/O	W17	I/O
K4	I/O	N9	V <sub>CCI</sub>	T14	HCLK	W19	I/O
K6	I/O	N11	GND	T16	I/O	W21	I/O
K8	V <sub>CCI</sub>	N13	GND	T18	I/O	W23	I/O
K10	I/O	N15	GND	T20	I/O	W25	I/O
K12	I/O	N17	I/O	T22	I/O	Y2	I/O
K14	I/O	N19	I/O	T24	I/O	Y4	I/O
K16	I/O	N21	I/O	U1	I/O	Y6	I/O
K18	I/O	N23	V <sub>CCR</sub>	U3	I/O	Y8	I/O
K20	V <sub>CCA</sub>	N25	V <sub>CCA</sub>	U5	V <sub>CCI</sub>	Y10	I/O
K22	I/O	P2	I/O	U7	I/O	Y12	I/O
K24	I/O	P4	I/O	U9	I/O	Y14	I/O
L1	I/O	P6	I/O	U11	I/O	Y16	I/O
L3	I/O	P8	I/O	U13	I/O	Y18	I/O
L5	I/O	P10	I/O	U15	I/O	Y20	NC
L7	I/O	P12	GND	U17	I/O	Y22	I/O
L9	I/O	P14	GND	U19	I/O	Y24	NC
L11	I/O	P16	I/O	U21	I/O		
L13	GND	P18	I/O	U23	I/O		
L15	I/O	P20	NC	U25	I/O		
L17	I/O	P22	I/O	V2	V <sub>CCA</sub>		
L19	I/O	P24	I/O	V4	I/O		
L21	I/O	R1	I/O	V6	I/O		
L23	I/O	R3	I/O	V8	I/O		

## 329-Pin PBGA

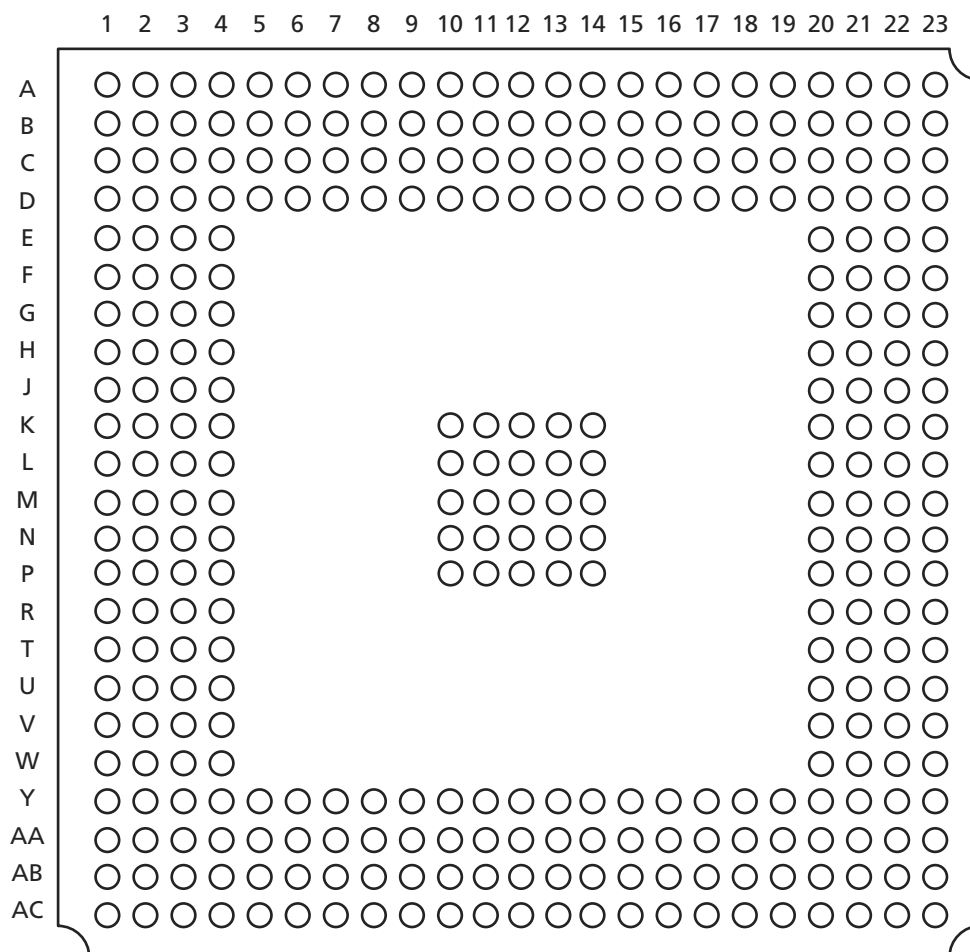


Figure 2-7 • 329-Pin PBGA (Top View)

### Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

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